

LATIN AMERICAN ELECTRON DEVICES CONFERENCE

PUEBLA, MEXICO 4-6 JULY, 2022









CONTACT

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IMPORTANT DATES

Paper submission: April 29th, 2022

Author notification: May 29th, 2022

Camera-ready and Video presentation:

June 3rd, 2022

CONFERENCE DATES: JULY 4TH-6TH 2022

CALL FOR PAPERS

LAEDC is the premiere Latin-American Electron Devices and related fields conference sponsored by IEEE's Electron Device society (EDS). Its main goal is to bring together specialists from Industry and Academia in all Electron Device related fields. This fourth edition will take place as a hybrid event and will also have a strong component of technology based Humanitarian Projects and STEM. The conference will be geared for students as well as young researchers and practitioners.

Authors are required to present online or in-person at the scheduled time to check or clarify the presentation and answer questions in sync with the live conference.

Proceedings will be published by IEEE and the accepted papers will be available on IEEE Xplore®. The best papers presented in the conference will be considered for publication in a special issue of the Journal of the Electron Devices Society JEDS

TOPICS OF INTEREST

Topics of interest include

- ◆ All electron-based devices
- ◆ Electron Devices for Quantum Computing
- ♦ RF-MMW-5G
- Semiconductor-, MEMS- and Nanotechnologies
- ◆ Packaging, 3D integration
- Sensors and actuators
- ◆ Display technology
- Modeling and simulation

- Biomedical Devices
- ◆ Circuit-device interaction
- ◆ Novel materials and process modules
- ◆ Technology roadmaps
- Electron device engineering education
- ◆ Electron device outreach
- Optoelectronics, photovoltaic and photonic devices and systems
- ◆ Humanitarian Projects

Follow all details and instructions visiting our conference web site https://attend.ieee.org/laedc-2022

Papers should be presented in English following the IEEE Transactions format for Conference Proceedings https://www.ieee.org/conferences/publishing/templates.html

Please adhere to the following instructions: Papers must not exceed 4 pages in length. Please ignore the header. Do not number your pages. Authors are required to include the Digital Object Identifier (DOI), where available. Each reference cited must have a complete list of authors (no et al.), complete titles, first and last pages numbers, month and year. Do not include authors' bios and photos.